

Notice of References Cited	Application/Control No. 10/814,376	Applicant(s)/Patent Under Reexamination IVANCIC ET AL.	
	Examiner Bobby Ramdhanie, Ph.D.	Art Unit 1709	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,742,050	04-1998	Amirav et al.	250/288
*	B	US-6,495,825	12-2002	Chace et al.	250/288
	C	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Gunther, Detlef, Jackson, S. E.; Longerich, H. P. "Laser ablation and arc spark solid sample introduction into inductively coupled plasma mass spectrometer." Spectrochimica Acta Part B. 1999, 54, 381-409.
	V	McKelvy, M. L.; Britt, T. R.; Davis, B. L.; Gillie, J. K.; Lentz, L. A.; Leugers, A.; Nyquist, R. A.; Putzig, C. L. "Infrared Spectroscopy." Analytical Chemistry. 1996, 68, 93R-160R.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.